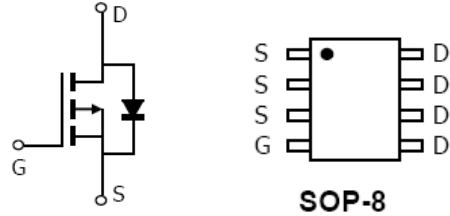


**P-Channel Enhancement Mode Field Effect Transistor**

● **Features**

$V_{DS}$	$R_{DS(ON)max}$	$I_D$
-30V	13 mΩ@-20V	-12A
	15 mΩ@-10V	
	18 mΩ@-5V	

● **Pin Configurations**



● **General Description**

The HG12P30SA uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , and ultra-low low gate charge with a 25V gate rating. This device is suitable for use as a load switch or in PWM applications.

-RoHS Compliant

-Halogen Free

● **Absolute Maximum Ratings @ $T_A=25^{\circ}C$  unless otherwise noted**

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	$V_{DSS}$	-30	V
Gate-Source Voltage	$V_{GSS}$	$\pm 25$	V
Drain Current (Continuous) *AC	$I_D$	$T_A=25^{\circ}C$	-12
		$T_A=70^{\circ}C$	-10
Drain Current (Pulse) *B	$I_{DM}$	-60	A
Power Dissipation	$P_D$	$T_A=25^{\circ}C$	3
		$T_A=70^{\circ}C$	2.1
Operating Temperature/ Storage Temperature	$T_J/T_{STG}$	-55~150	$^{\circ}C$

## Electrical Characteristics

$T_A=25^{\circ}\text{C}$  unless otherwise noted

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
<b>Static</b>						
Drain-Source Breakdown Voltage	$V_{(BR)DSS}$	$V_{GS} = 0V, I_D = -250 \mu A$	-30	--	--	V
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = -30 V, V_{GS} = 0V$	--	--	-1	$\mu A$
Gate Threshold Voltage	$V_{GS(TH)}$	$V_{GS} = V_{DS}, I_{DS} = -250 \mu A$	-1.6	-2.0	-3	V
Gate Leakage Current	$I_{GSS}$	$V_{GS} = \pm 25V, V_{DS} = 0V$	--	--	100	nA
Drain-Source On-state Resistance	$R_{DS(on)}$	$V_{GS} = -20V, I_D = -10A$	--	10	13	m $\Omega$
		$V_{GS} = -10V, I_D = -10A$	--	11	15	m $\Omega$
		$V_{GS} = -5V, I_D = -10A$	--	15	18	m $\Omega$
Forward Transconductance	$g_{FS}$	$V_{DS} = -5V, I_D = -10A$	--	26	--	S
Diode Forward Voltage	$V_{SD}$	$I_{SD} = -1A, V_{GS} = 0V$	--	-0.72	-1.0	V
Maximum Body-Diode Continuous Current	$I_S$		--	--	-4.2	A
<b>Switching</b>						
Total Gate Charge	$Q_g$	$V_{GS} = -10V, V_{DS} = -15V,$ $I_D = -12A$	--	46.64	60.63	nC
Gate-Source Charge	$Q_{gs}$		--	7.84	10.2	nC
Gate-Drain Charge	$Q_{gd}$		--	9.96	12.95	nC
Turn-on Delay Time	$t_{d(on)}$	$V_{GS} = -10V, V_{DS} = -15V,$ $R_L = 1.25\Omega, R_{GEN} = 3\Omega$	--	19.24	38.48	ns
Turn-on Rise Time	$t_r$		--	8.56	17.12	ns
Turn-off Delay Time	$t_{d(off)}$		--	69.8	139.6	ns
Turn-off Fall Time	$t_f$		--	18.52	37.04	ns
<b>Dynamic</b>						
Input Capacitance	$C_{iss}$	$V_{GS} = 0V, V_{DS} = -15V, f = 1MHz$	--	2777.96	--	pF
Output Capacitance	$C_{oss}$		--	380.67	--	pF
Reverse Transfer Capacitance	$C_{rss}$		--	217.7	--	pF

A: The value of  $R_{\theta JA}$  is measured with the device mounted on 1in<sup>2</sup> FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^{\circ}\text{C}$ . The value in any given application depends on the user's specific board design.

B: Repetitive rating, pulse width limited by junction temperature.

C: The current rating is based on the  $t \leq 10s$  junction to ambient thermal resistance rating.

# Typical Electrical and Thermal Characteristics

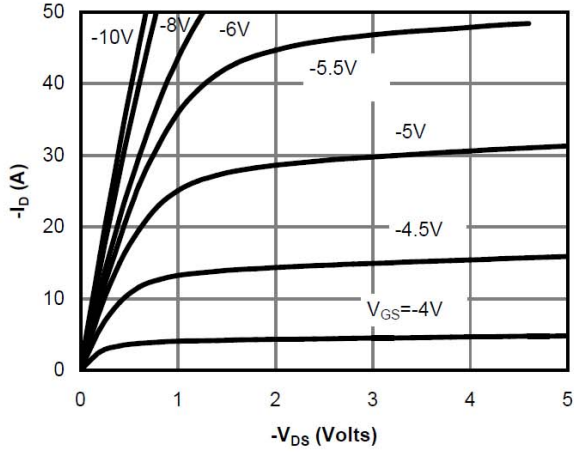


Fig 1: On-Region Characteristics

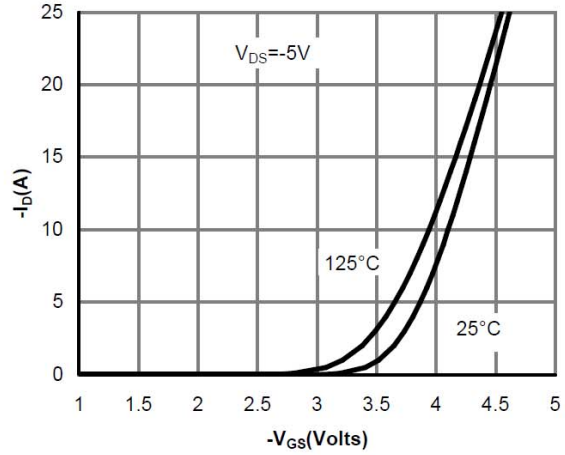


Figure 2: Transfer Characteristics

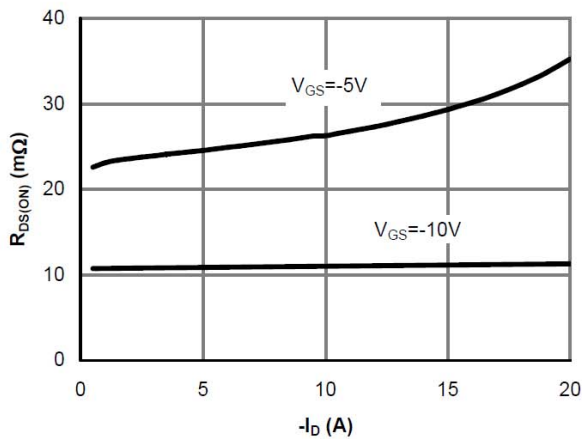


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

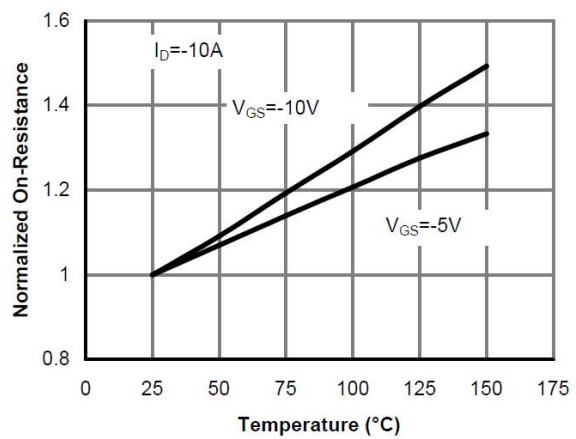


Figure 4: On-Resistance vs. Junction Temperature

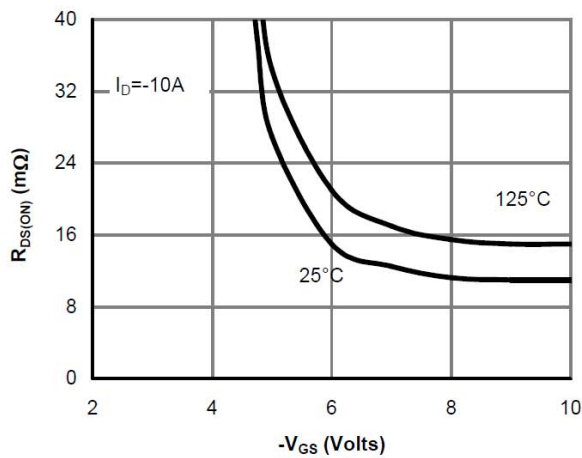


Figure 5: On-Resistance vs. Gate-Source Voltage

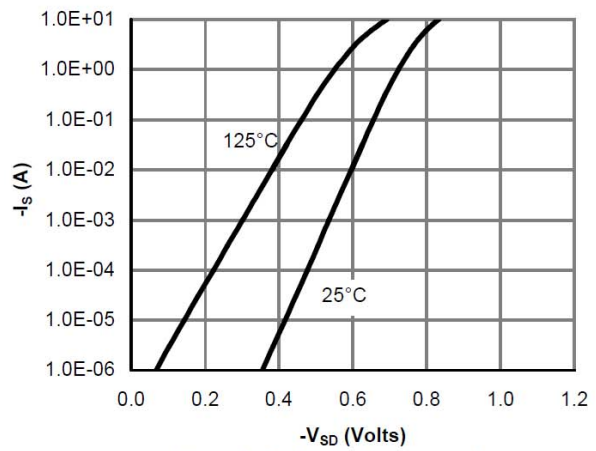


Figure 6: Body-Diode Characteristics

# Typical Electrical and Thermal Characteristics

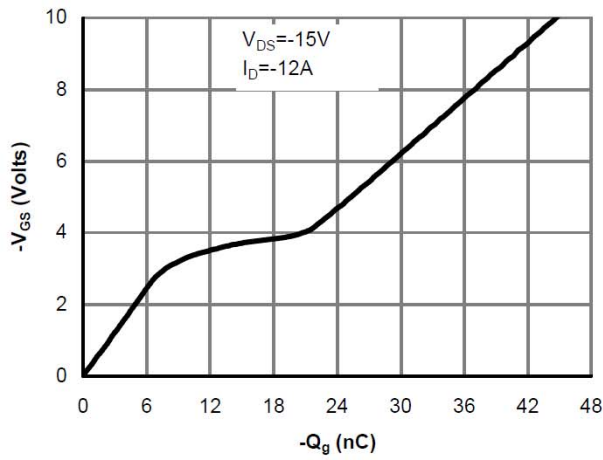


Figure 7: Gate-Charge Characteristics

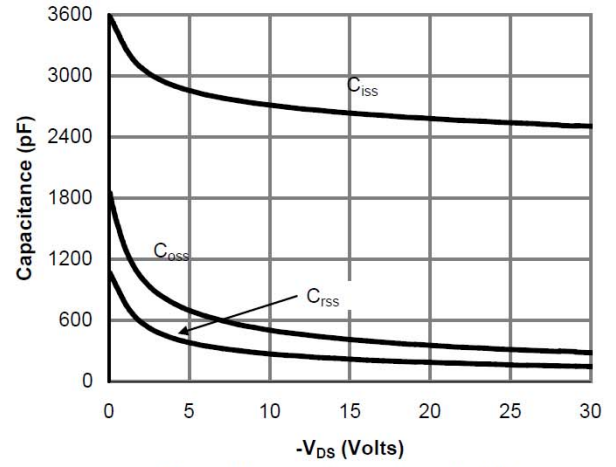


Figure 8: Capacitance Characteristics

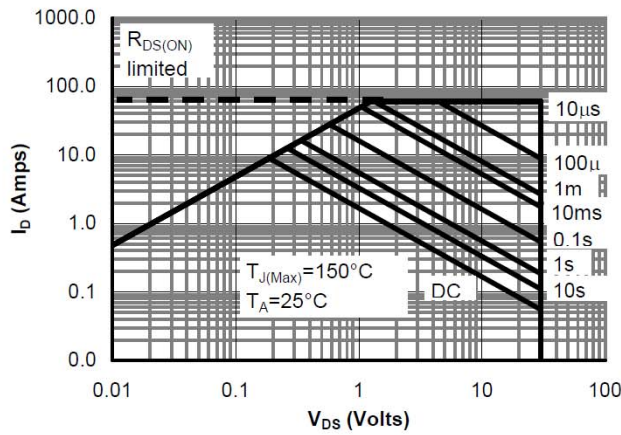


Figure 9: Maximum Forward Biased Safe Operating Area

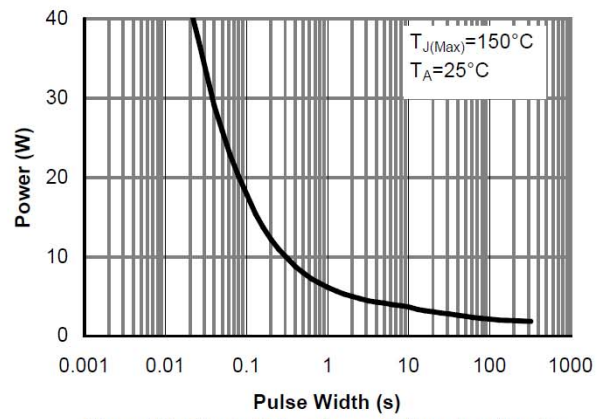


Figure 10: Single Pulse Power Rating Junction-to-Ambient

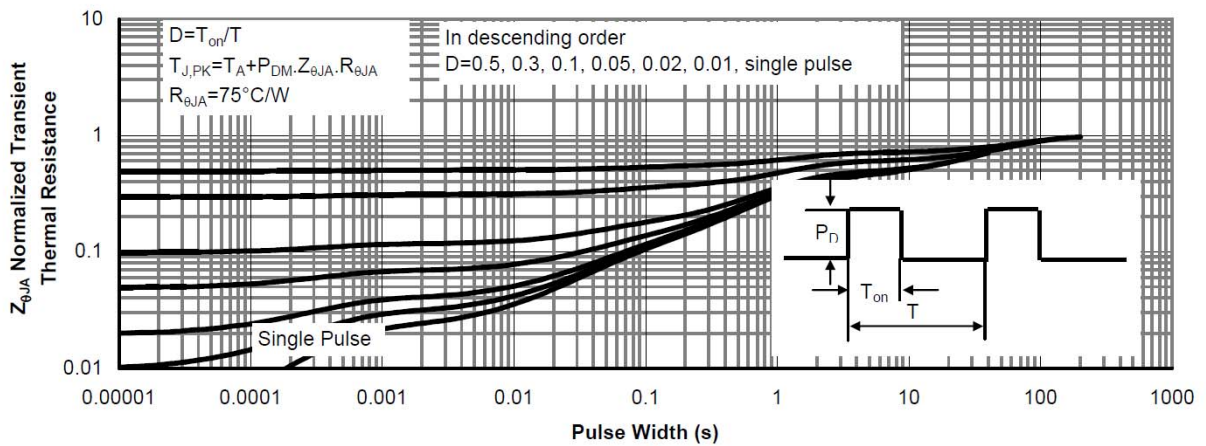


Figure 11: Normalized Maximum Transient Thermal Impedance

## Package Information

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